

NSG 3040A

THE SMART 4 KV SOLUTION FOR CE APPLICATIONS



- One box solution system
- Surge voltage to 4.8 kV
- EFT/Burst to 4.8 kV / 1 MHz
- PQT to 16 A / 300 VAC & DC
- Easy to use 7" color touch screen
- Parameters can be changed while test running
- Wide range of optional test accessories

Teseq's new NSG 3040A is an easy-to-use multifunction generator that simulates electromagnetic interference effects for immunity testing in conformity with international, national and manufacturers' standards including the latest IEC/EN standards. The NSG 3040A system is designed to fulfill conducted EMC test requirements for CE mark testing, which generally include combination wave surge, Electrical Fast Transient (EFT) pulses and Power Quality Testing (PQT). Extensive expansion capabilities enable the system to be configured for a much broader range of applications.

Featuring an innovative, modular design, the NSG 3040A is a versatile system that can be configured for basic testing needs and expanded to meet the needs of sophisticated test laboratories.

Using state-of-the-art components, the self-contained modules set new standards with respect to switching and phase accuracy and exceed the existing standards' requirements.

A 7" touch panel display with superb contrast and color makes controlling the NSG 3040A easy. For fast and efficient data entry, input devices include an integrated keyboard and a thumbwheel with additional keys for sensitivity adjustment. To achieve quick, reliable results in a development environment a standardized test can be initiated with just a few "clicks" using the integrated Test Assistance (TA) function.

Convenient touch input buttons make each parameter's value highly visible and allow the user to quickly select and modify all settings. A stylus is not necessary, and ramp functions can be programmed quickly and easily. Multi-step test procedures can be created and their sequence or parameter values can be changed easily.

With expert mode users can make manual parameter changes using the thumbwheel while a test is under way, providing an effective and fast method for identifying critical threshold values.

The NSG 3040A has an Ethernet port for external PC control. The Windows-based control software simplifies test programming and compilation of complex test sequences with various types of tests. Test reports can be generated during the test operation, allowing the operator to enter observations as the test progresses and increasing the efficiency of long-term tests.

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The NSG 3040A performs tests according to the following specifications:

Combination wave pulse 1, 2/50 - 8/20 μ s (Hybrid-Surge pulse)

Pulse conforms to IEC/EN 61000-4-5

Parameter	Value
Pulse voltage (open circuit):	\pm 200 V to 4.8 kV (in 1 V steps)
Pulse current (short circuit):	\pm 100 A to 2.4 kA
Impedance:	2/12 Ω
Polarity:	positive / negative / alternate
Pulse repetition:	10 s, up to 9'999 s (in 1 s steps)
Test duration:	1 to 99'999 pulses, continuous
Phase synchronization:	asynchronous, synchronous 0 to 359° (in 1° steps)
Coupling:	IEC / external

Burst (EFT) 5/50 ns

Pulse conforms to IEC/EN 61000-4-4

Parameter	Value
Pulse amplitude:	\pm 200 V to 4.8 kV (in 1 V steps) - open circuit \pm 100 V to 2.4 kV (50 Ω matching system)
Burst frequency:	100 Hz to 1000 kHz
Polarity:	positive / negative / alternate
Repetition time:	10 ms to 9'999 ms
Burst duration:	0.01 ms to 9'999 ms, single pulse
Test duration:	1 s to 9'999s, 1 min to 1600 min, endless
Phase synchronization:	asynchronous, synchronous 0 to 359° (in 1° steps)
Coupling:	internal / external

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Dips & Interrupts

conforms to IEC/EN 61000-4-11, IEC/EN 61000-4-29

Parameter	Value
Dips & Interrupts:	From EUT voltage input to 0 V, 0% ⁽¹⁾
Uvar with optional variac:	depending on model (VAR 3005A)
Uvar with step transformer:	0, 40, 70, 80% (INA 650xA)
Peak inrush current capability:	> 500 A (at 230 V)
Switching times:	1 to 5 μ s (100 Ω load)
Event time (T-Event):	20 μ s to 9999 s, 0.5 to 9'999 cycles
Repetition time:	10 ms to 9'999 ms, 1 to 9'999 s
Test duration:	1 to 99'999 events, endless
Phase synchronization:	asynchronous, synchronous 0 to 359° (in 1° steps)

(1) In combination with VAR 3005A, effective minimal dip voltage \sim 8 V. As specified in IEC 61000-4-11, chapt. 5.1 a test voltage level from 0% to 20% of the rated voltage is considered as a total interruption.

Variation test (with VAR 3005A only)

conforms to IEC/EN 61000-4-11

Parameter	Value
Uvar with optional variac:	up to approx. 265 V (in 1 V steps) or up to 115% Uin (in 1% steps)
Decreasing time Td:	1 ms to 9.999 s, 0.5 to 9999 cycles, abrupt
Time at reduced voltage Ts:	1 ms to 9.999 s, 0.5 to 9999 cycles,
Increasing time Ti:	1 ms to 9.999 s, 0.5 to 9999 cycles,
Repetition time:	1 s to 9'999 s
Events:	1 to 99'999

Pulsed magnetic field in conjunction with MFC 30

conforms to IEC/EN 61000-4-9

Parameter	Value
Field:	100 to 1200 A/m
Polarity:	positive / negative / alternate
Repetition time:	10 s to 9999s (in 1 s steps)
Impedance:	2 Ω
Coil / impedance factor:	0.01 to 100.00
Test duration:	1 to 9'999 pulses, endless
Phase synchronization:	asynchronous, synchronous 0 to 359° (in 1° steps)

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Power magnetic field in conjunction with MFT 30 or MFO 6501 and MFC 30 & MFC 300
conforms to IEC/EN 61000-4-8

Parameter	Value
Field:	1 to max. 40 A/m
Frequency:	50 or 60 Hz
Coil factor:	0.01 to 100
Test duration:	1 s to 99'999 s, endless

Internal coupling network

Parameter	Value
EUT supply:	1-phase
EUT VAC:	Up to 300 Vrms *, 50 / 60 Hz (phase - neutral)
EUT VDC:	Up to 300 VDC
EUT current	1 x 16 Arms continuous (over heat protected)
Connections: Front panel:	- EUT: 4mm banana plug - Burst OUT 50 Ω SHV - Trigger out BNC
Rear panel	- EUT supply: banana plug 4 mm - Additional ground connector - Instrument supply 85 V to 264 VAC - Connector surge HV – COM
Surge	Standard coupling as per IEC 61000-4-5
Coupling mode	Line to Line Line(s) to ground
Mains decoupling:	1.5 mH 0% + 35%
Decoupling attenuation:	Residual pulse voltage on EUT power supply inputs 15 % max. Residual voltage on non-pulsed EUT power supply inputs 15 % max.
EFT (Burst)	Standard coupling all lines to ref ground (GND) IEC / EN 61000-4-4
	L, N, PE to ref GND
	Any lines and combinatio to ref GND:
	L to ref GND
	N to ref GND
	PE to ref GND
	L, N to ref GND
	L, PE to ref GND
	N, PE to ref GND
PQT:	Dips & interrupts to phase L

* Below 24 VAC synchronisation not guaranteed, asynchronous mode only

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Technical specification

Instrument supply	85 to 265 VAC, 50 / 60 Hz
Dimensions NSG 3040A:	19"; 3 HU, 448 x 154 x 500 mm (W x H x D)
Weight NSG 3040A:	approx. 22 kg (49 lbs)

Options

Type	Description
CDN 3043A-C32	Three phase automatic coupling decoupling network, 3x480 V / 32 A
CDN 3425	Burst EFT capacitive coupling clamp for data line coupling
CDN 117A-C4-4-1	Coupling networks for unsymmetrical signal-/data lines (surge)
CDN 118A-C4-4-1	Coupling networks for symmetrical signal-/data lines (surge)
CDN HSS-2	Coupling network for 2 kV surge pulse 1.2 / 50 μ s IEC/EN 61000-4-5 on unshielded symmetrical high speed telecom lines (Ethernet)
PVF BKIT 1	Burst/EFT verification set
MD 210	Voltage differential probe 3.5 kV / 7 kV
MD 300	Current probe 5 kA

Accessories for IEC/EN 61000-4-11

Type	Description
TVT 1-250-16	Manual step transformer, 16 AAC, 0/40/70/80%
VAR 3005A-S16	Automatic single variable transformer, 1 x 16 A

Accessories for IEC/EN 61000-4-8/-4-9

Type	Description
MFO 6501A	Manual magnetic field option for -4-8
MFC 30	Magnetic field coil 1 x 1 m, with MFO max. 40 A/m -4-8; Surge* max. 1200 A/m -4-9
MFC 300	Magnetic field coil 1 x 1 m; max. 330 A/m -4-8

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